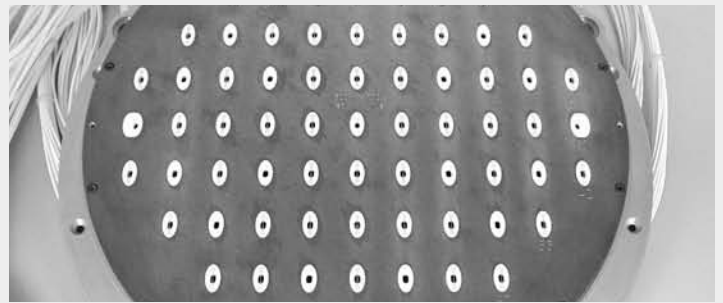


# T200/T300 BUTTONTILE™

CELADON™

200MM & 300MM PROBE CARDS FOR WAFER LEVEL RELIABILITY TESTING



T200 and T300 ButtonTile™ probe cards are designed for high-density, long-term, temperature-compensated wafer level reliability testing.

ButtonTile™ probe cards eliminate the need for constant monitoring and adjustments - after aligning the probe card, simply walk away and let the prober do its job.

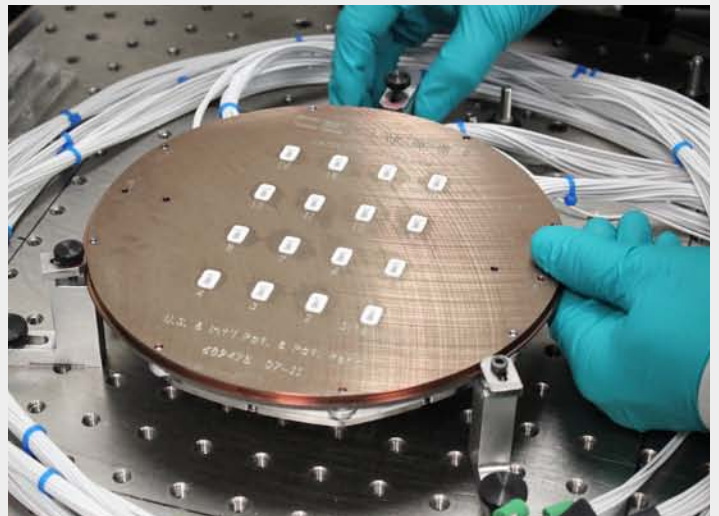
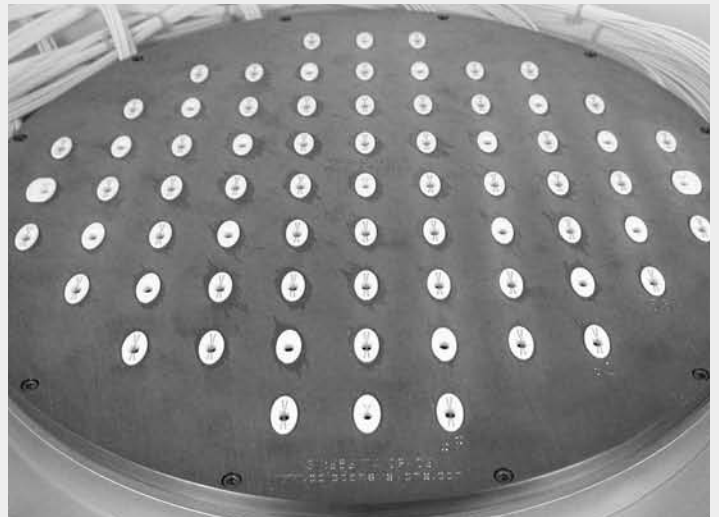
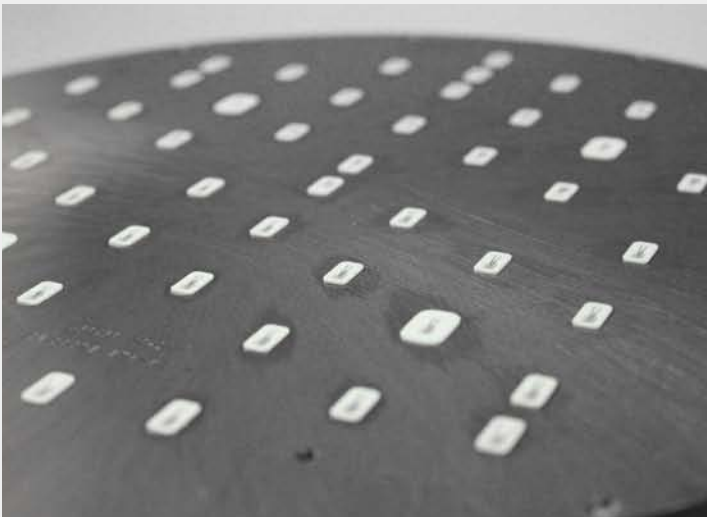
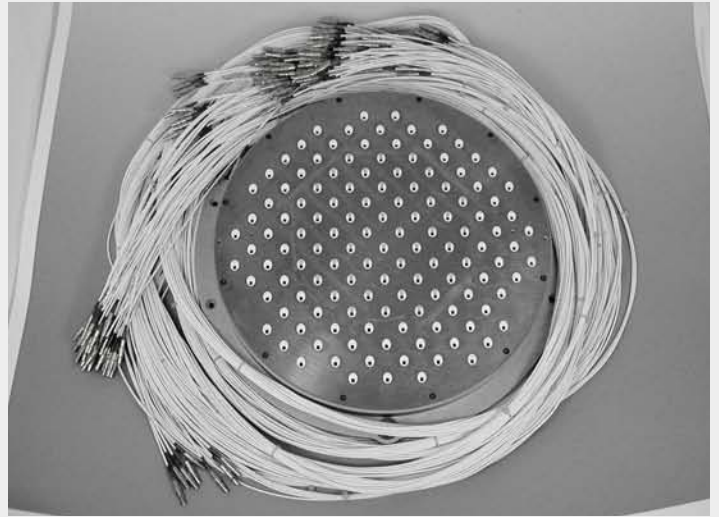
A 200mm T200 probe card can accommodate up to 5,000 probes, and a 300mm T300 probe card can accommodate up to 10,000 probes.

Low Leakage at 10 seconds:

- Leakage < 5fA/V from -65° to 75°C
- Leakage < 10 fA/V from 75° to 100°C
- Leakage < 50 fA/V from 100° to 150°C
- Leakage < 300 fA/V from 150° to 200°C
- Leakage < 1pA/V from 200° to 300°C

- Standard operating range -60° to 300°C, optional to 400°C

- Up to 5,000 probes per T200
- Up to 10,000 probes per T300
- Minimum pitch pattern-dependent
- Standard X-Y accuracy 10% pad size
- Standard Z variation: +/- 12 microns over entire probe card
- Coverage areas: T200 - 180mm; T300 - 280mm



# T200/T300 BUTTONTILE™